

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/608,505 | Applicant(s)/Patent Under Reexamination KAIJALA ET AL. | |
| | Examiner Kyung S. Lee | Art Unit 2832 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| | A | US-6,359,245 | 03-2002 | Wahls, Robert J. | 200/52R |
| | B | US-6,448,512 | 09-2002 | Cooper, Stephen R. W. | 177/144 |
| | C | US-5,720,523 | 02-1998 | Kawabata et al. | 297/338 |
| | D | US-4,385,863 | 05-1983 | Minor, Ray C. | 414/699 |
| | E | US-6,356,200 | 03-2002 | Hamada et al. | 340/667 |
| | F | US-4,361,741 | 11-1982 | Leskoverc et al. | 200/85A |
| | G | US-5,481,078 | 01-1996 | Asche, James E. | 200/85A |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.